

4/23/2015



**RELIABILITY MONITOR REPORT  
FOR**

**MFN 5 $\mu$ m Silicon Gate HV (S5HV)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX44291AUA
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The calculated failure rate for devices using this process is:

**FAILURE RATE:    MTTF (YRS): 2865    QUANTITY: 77    FAILS: 0    FITS: 39.8**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25    °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2014 and 3/31/2015 .

**Process Information:**

Process Description:            MFN 5µm Silicon Gate HV (S5HV)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1418	MAX44291AUA+	135°C	192 HRS	77	0	JAOD43001BQ
<b>Total:</b>						<b>0</b>	
<b>FAILURE RATE:</b>	<b>MTTF (YRS): 2865</b>		<b>QUANTITY: 77</b>		<b>FAILS: 0</b>	<b>FITS: 39.8</b>	